

ReMeCo: Reliable memristor-based in-memory neuromorphic computation

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Outline

- **Introduction**
- **DSE (Contribution I)**
- **Related work**
- **ReMeCo (Contribution II)**
- **Results (Contribution III)**
- **Conclusion**



Introduction

Motivation

Problem statement

Boom of ANN*

- Ubiquitous (e.g., NLP, CV, etc.)
- More complex

*ANN: Artificial Neural Network

Boom of ANN

- Ubiquitous (e.g., NLP, CV, etc.)
- More complex

Inefficient execution on conventional PEs*

- Memory Wall

*PE: Processing Element

Boom of ANN

- Ubiquitous (e.g., NLP, CV, etc.)
- More complex

Inefficient execution on conventional PEs

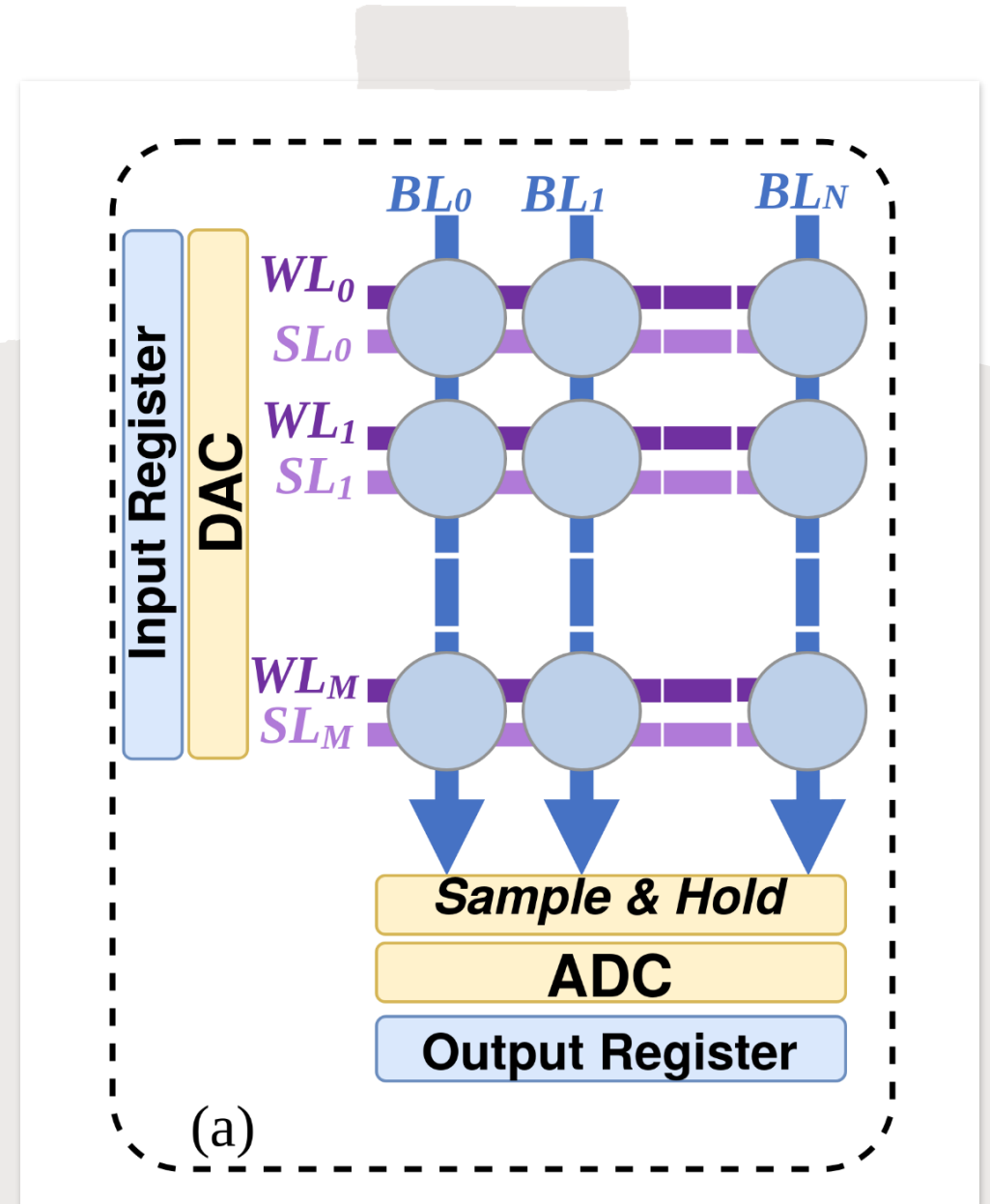
- Memory Wall

Computation In Memory

- SRAM/DRAM modification
- 3D stacked memories
- Memristors

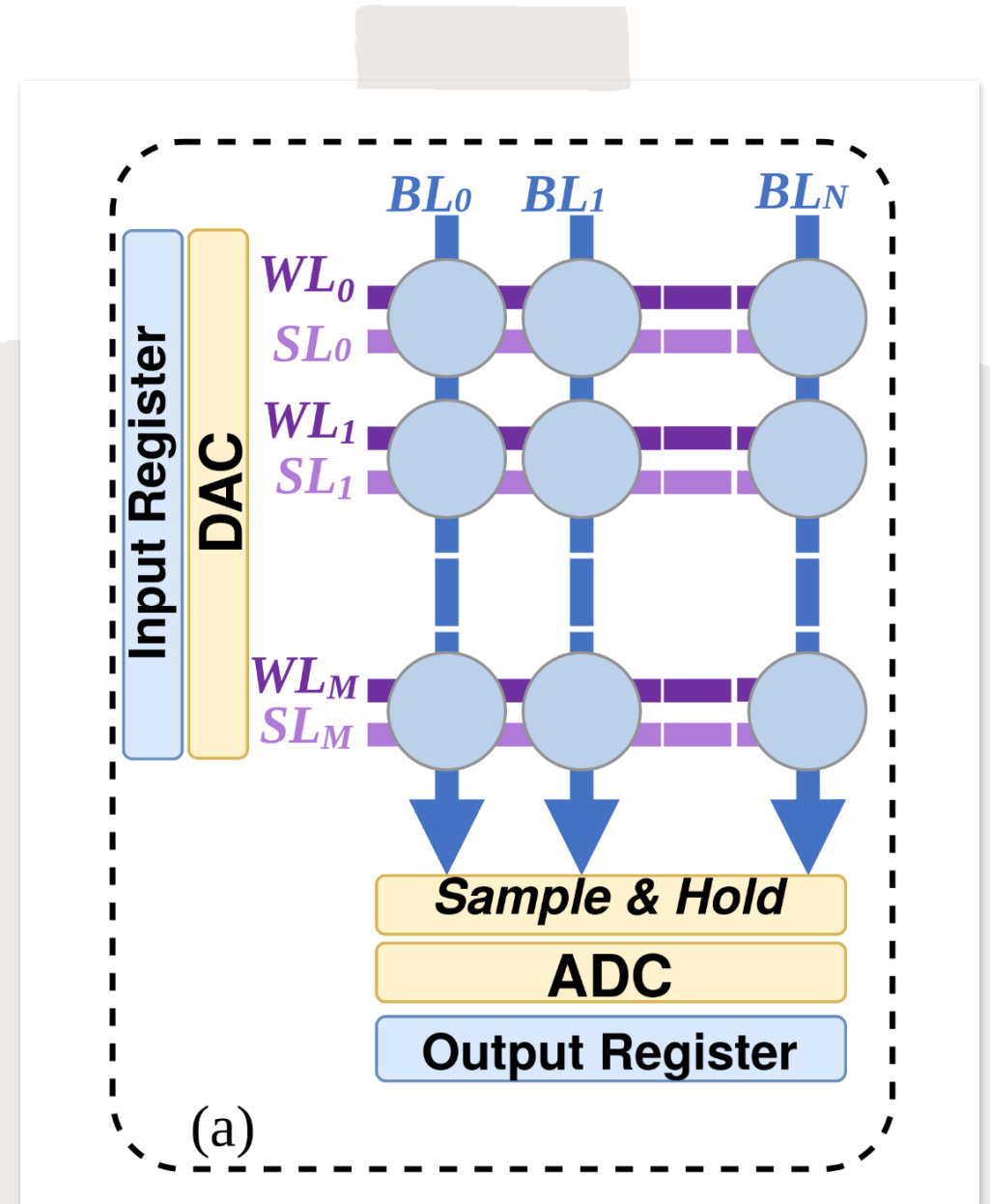
Memristor Crossbars

BL: Bit Line
WL: Word Line
SL: Source Line



Vector-Matrix Multiplication

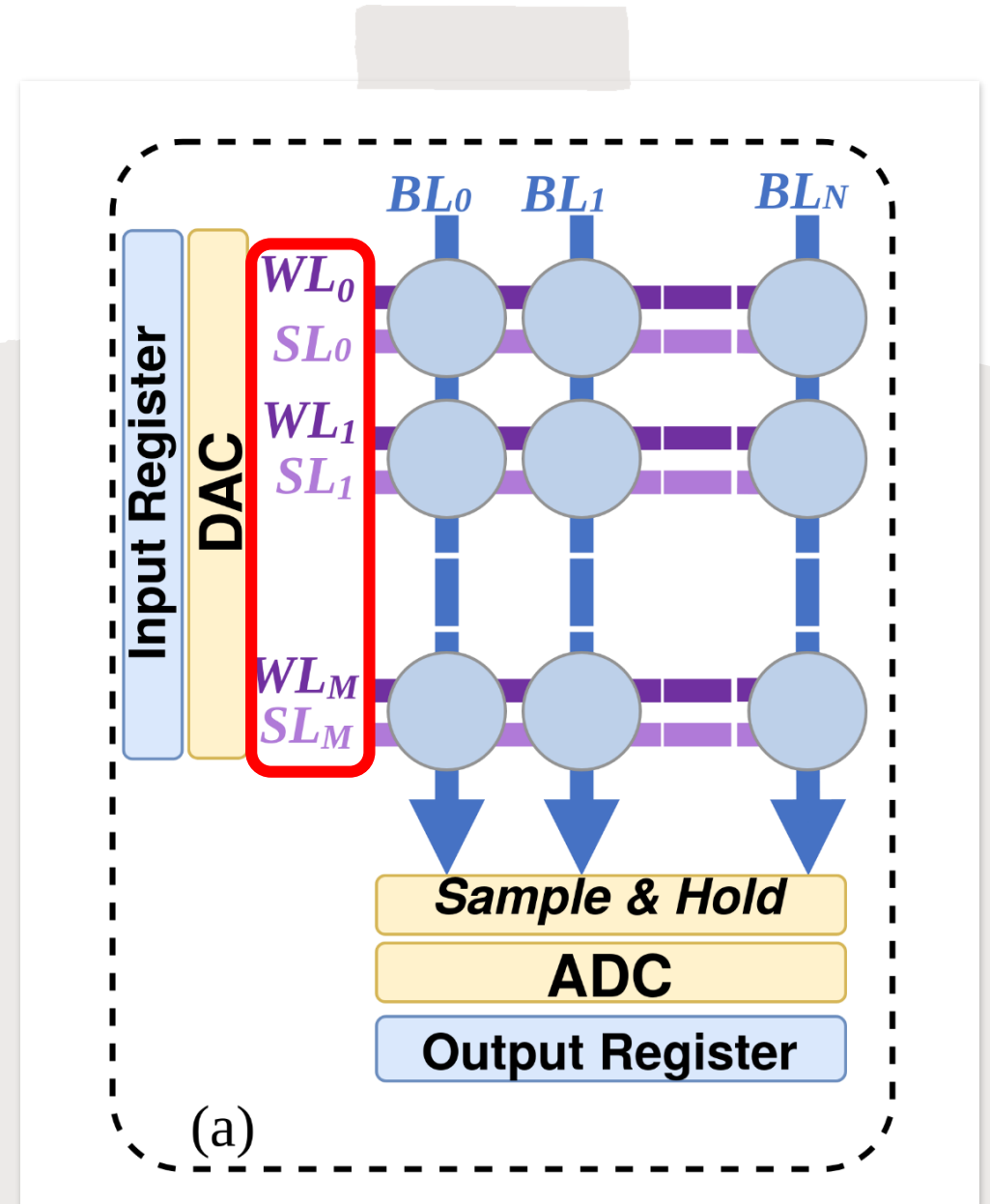
$$Out = In \times Weight$$



Vector-Matrix Multiplication

$$Out = In \times Weight$$

$In \rightarrow V$ (vector of voltages)

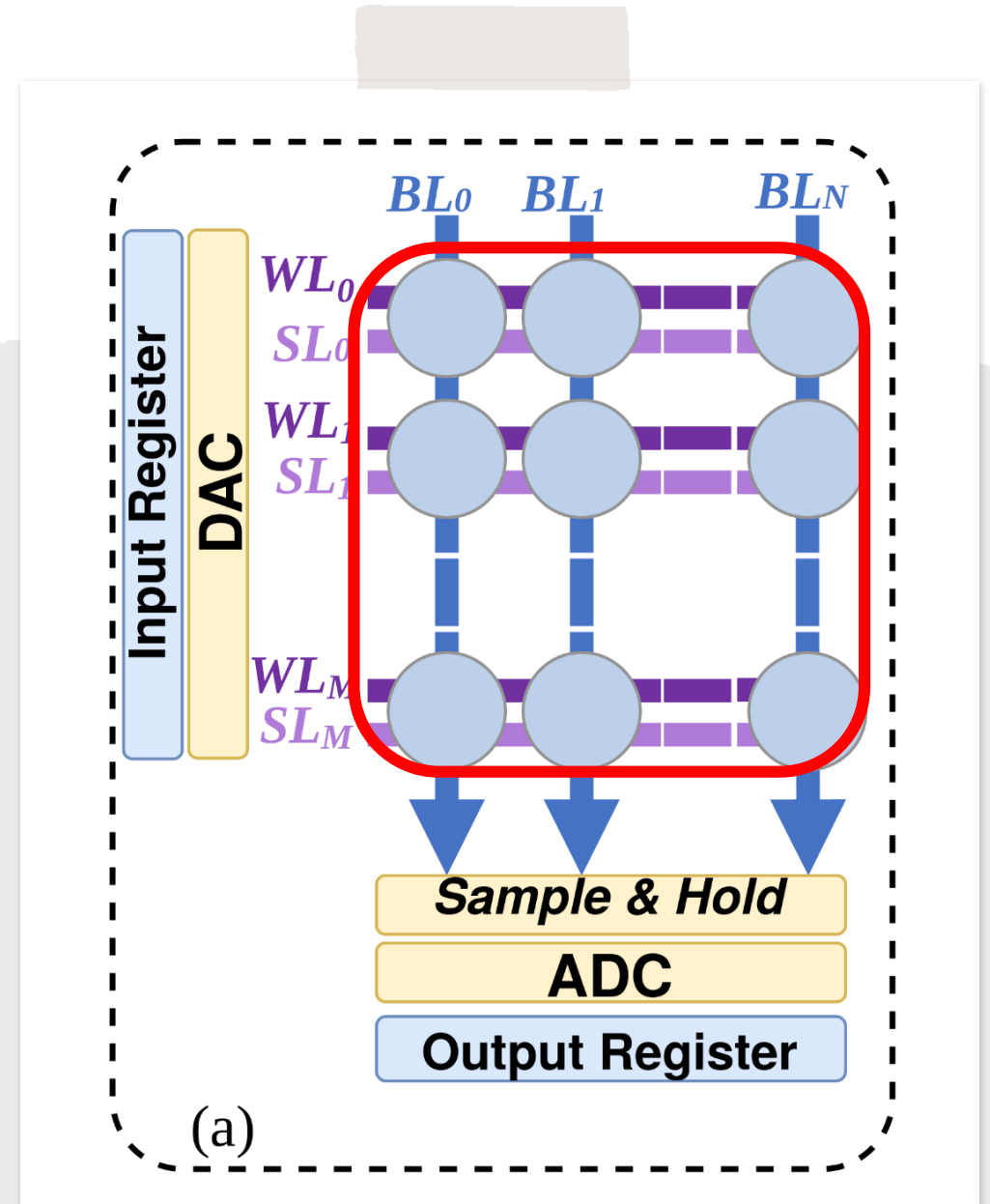


Vector-Matrix Multiplication

$$Out = In \times Weight$$

$In \rightarrow V$ (vector of voltages)

$Weight \rightarrow G$ (matrix of conductances)



Vector-Matrix Multiplication

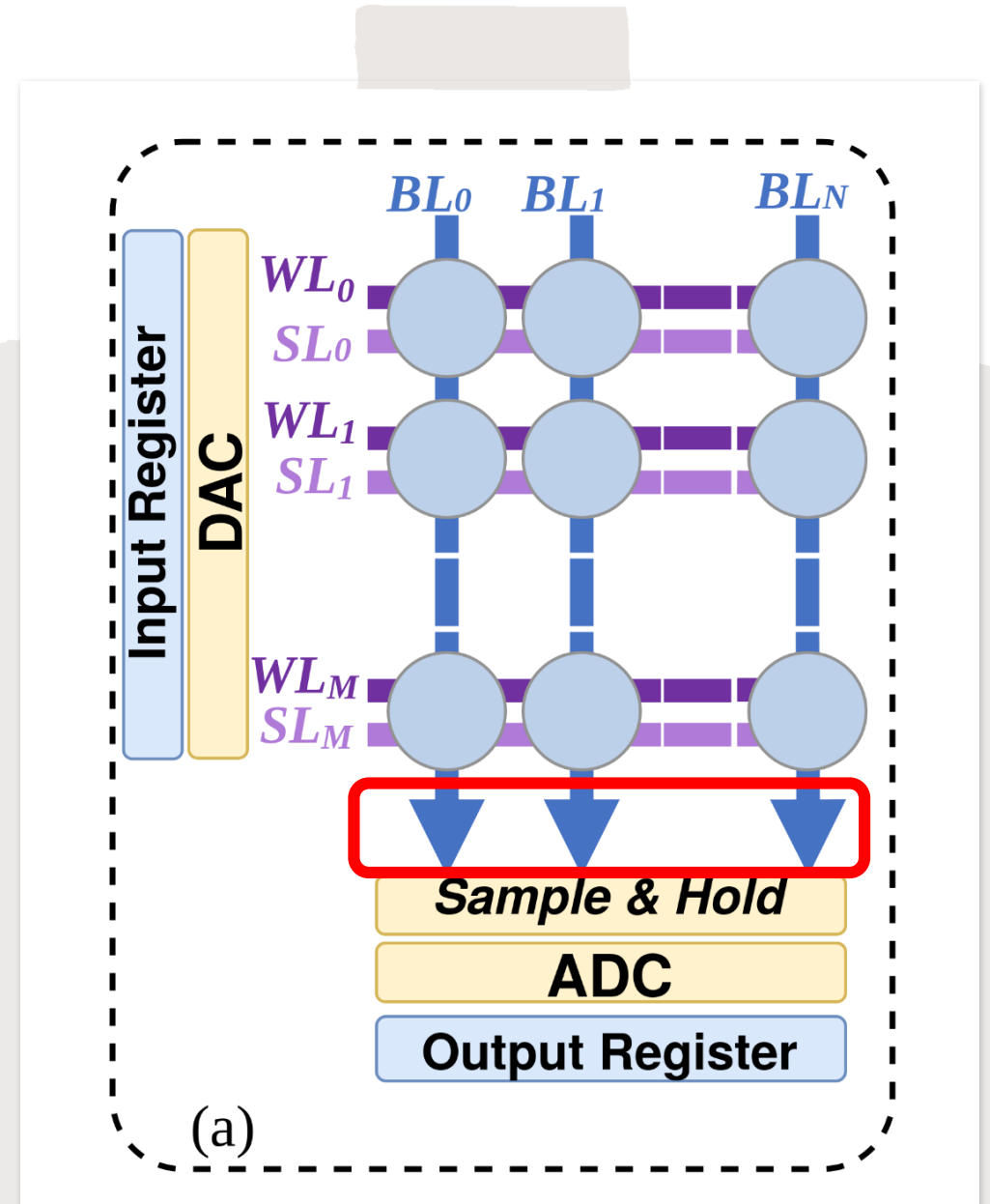
$$Out = In \times Weight$$

$In \rightarrow V$ (vector of voltages)

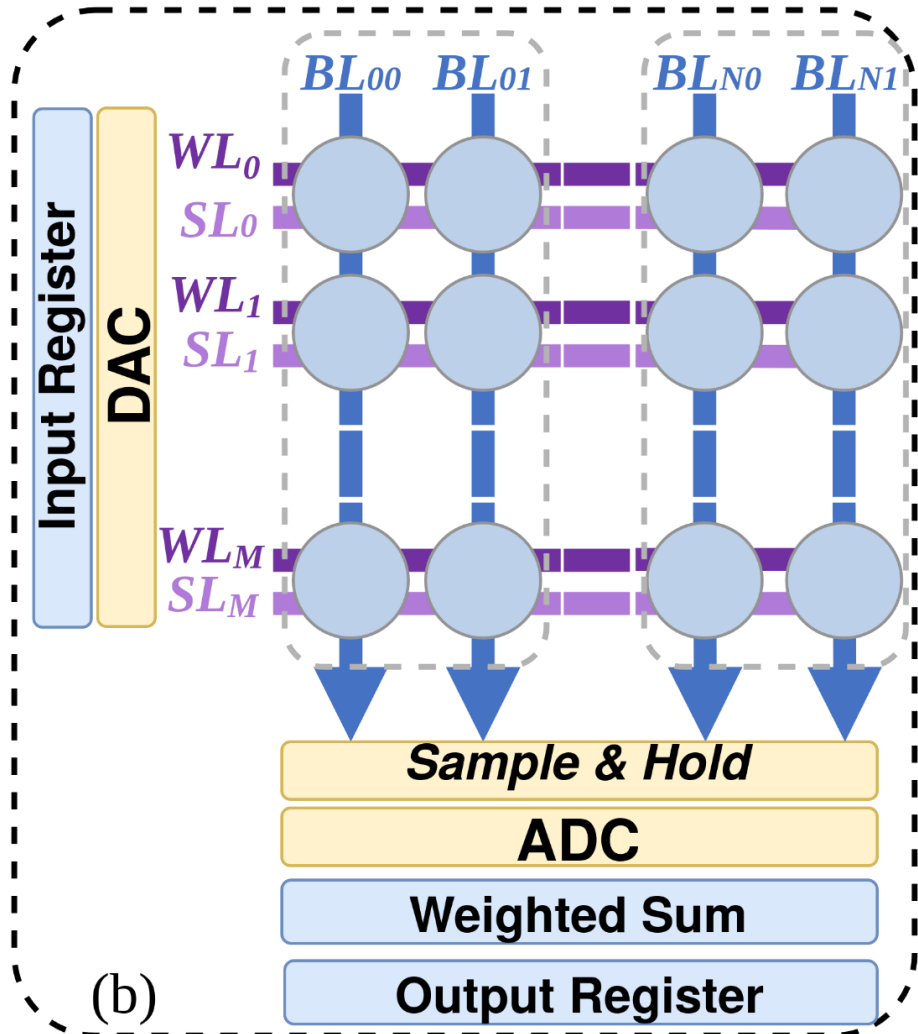
$Weight \rightarrow G$ (matrix of conductances)

$Out \rightarrow I$ (vector of currents)

$$I = V \times G$$



Bit-Slicing



Non-idealities

Stuck-at-fault

- Freezes in a state
- Inaccurate weight mapping



Non-idealities

Stuck-at-fault

- **Freezes in a state**
- **Inaccurate weight mapping**

IR-drop

- **Wire resistance**
- **Output current deviation**



Non-idealities

Stuck-at-fault

- Freezes in a state
- Inaccurate weight mapping

IR-drop

- Wire resistance
- Output current deviation

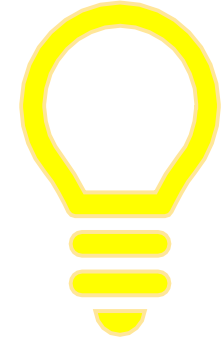
D2D variation

- Uncertain weight mapping



ReMeCo addresses these non-idealities using *smart hardware redundancy*

ReMeCo



- ***Key idea: apply redundancy to where it contributes most***

ReMeCo

- **Key idea: *apply redundancy to where it contributes most***
- **Hence, *limit hardware redundancy***

ReMeCo

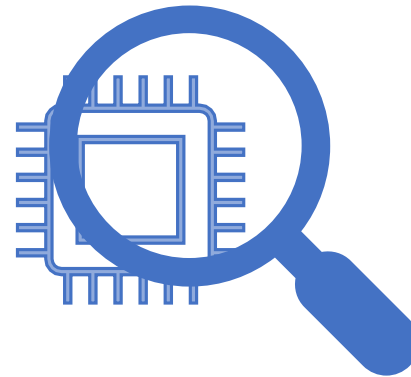
- **Key idea: *apply redundancy to where it contributes most***
- **Hence, *limit hardware redundancy***
- ***By identifying sensitive neurons and sensitive layers in an ANN***

ReMeCo

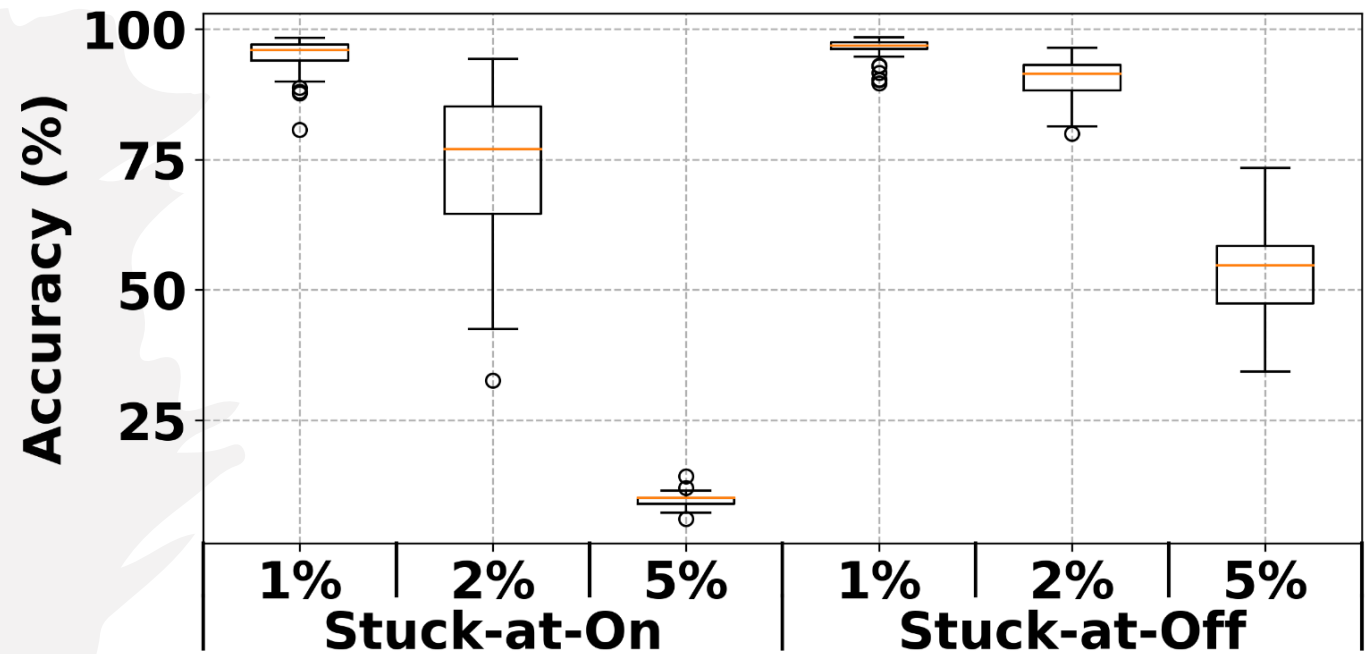
- **Key idea:** *apply redundancy to where it contributes most*
- **Hence, limit hardware redundancy**
- **By identifying sensitive neurons and sensitive layers in an ANN**
- **NOTE:** *Device independent*

Design space exploration of the effects and importance of different non-idealities

Contribution I

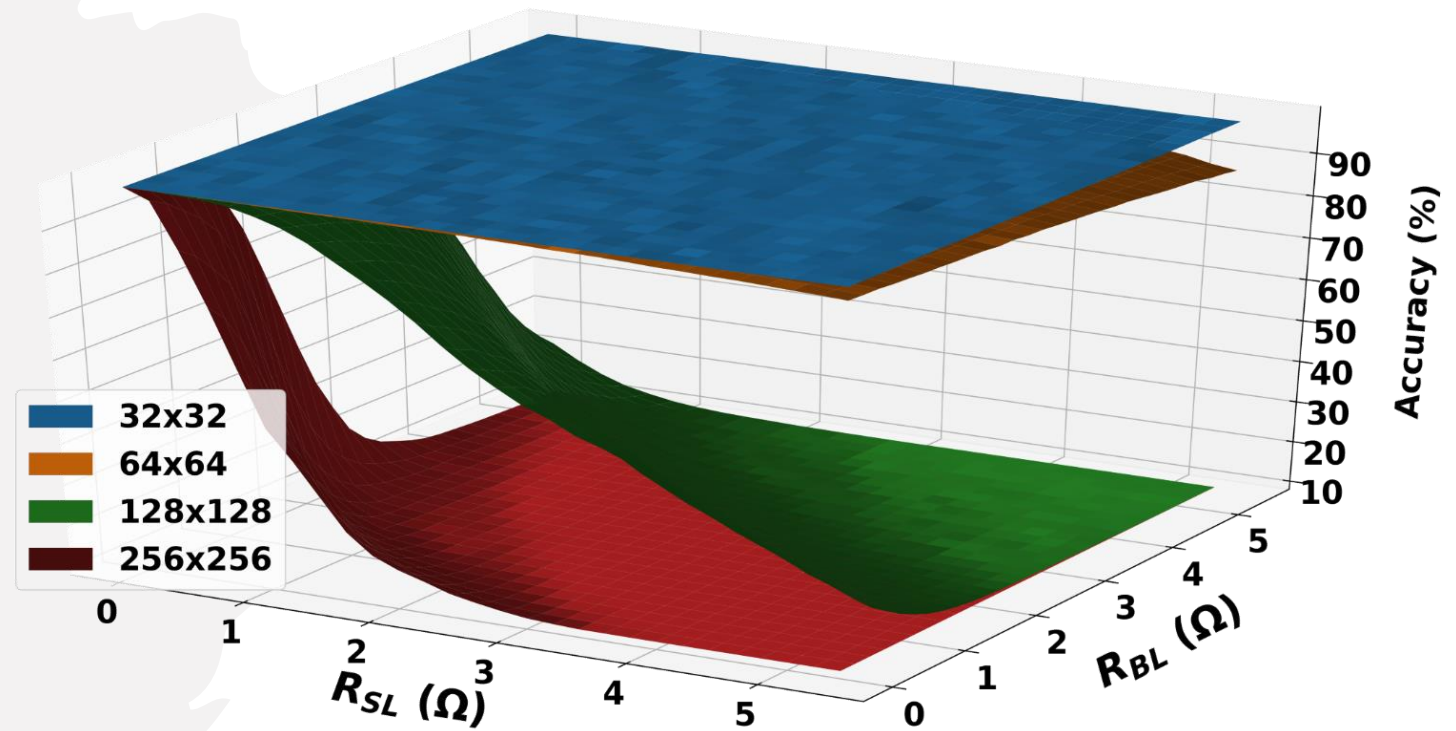


Stuck-at-fault



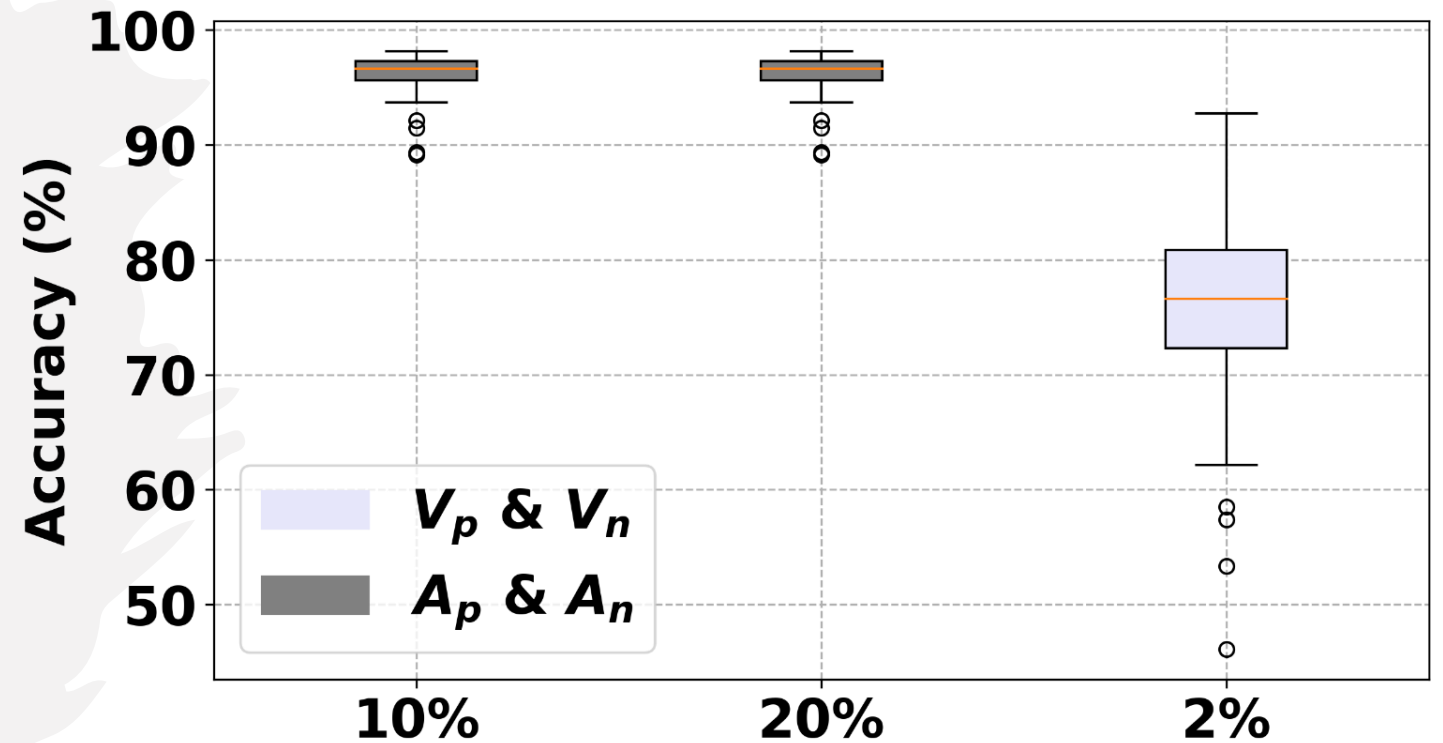
IR-drop

- *Wire resistance*



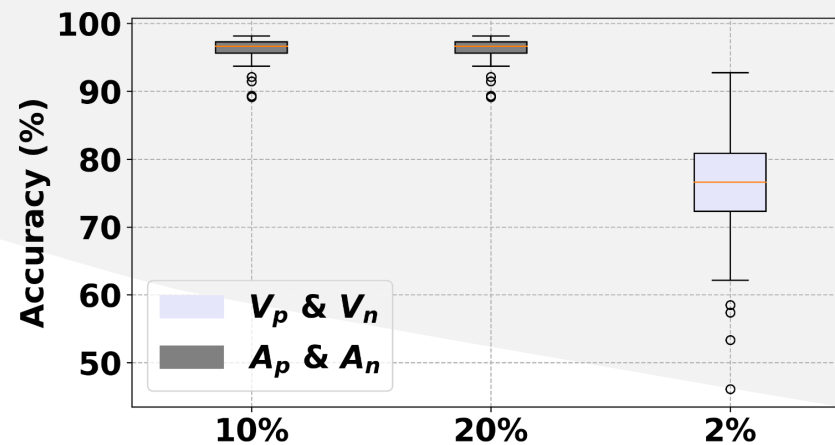
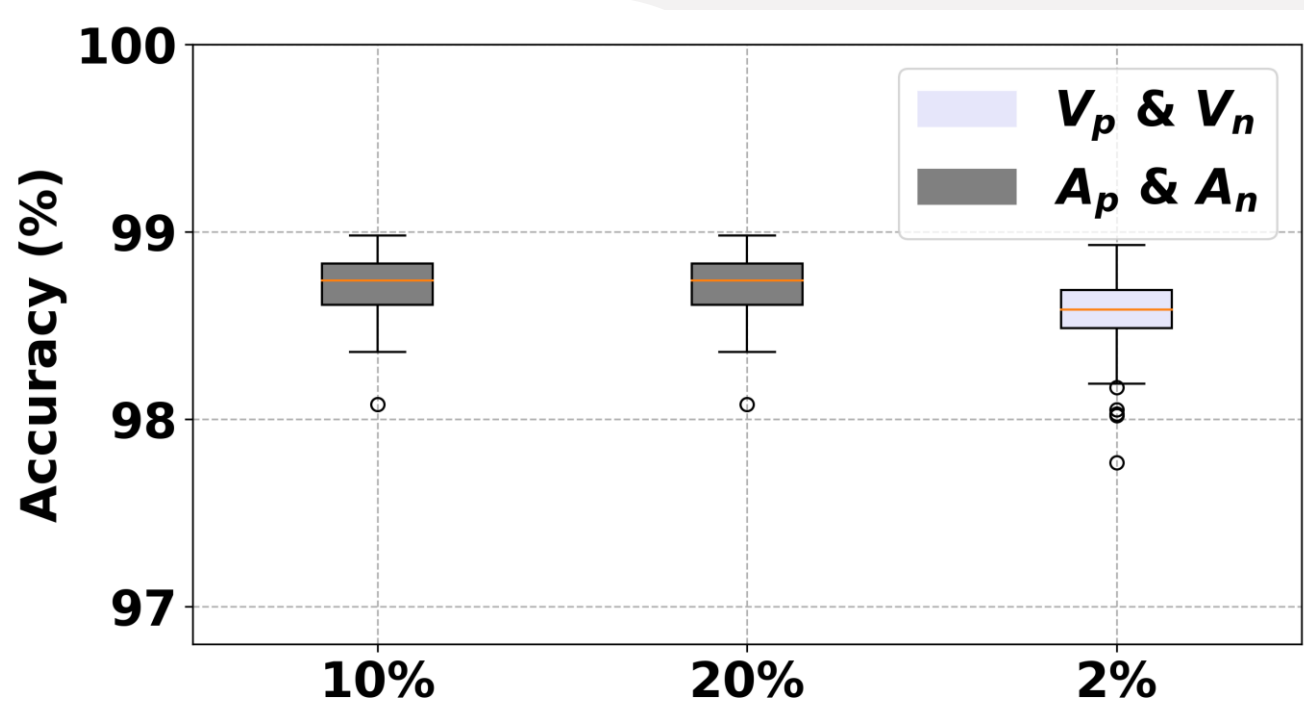
D2D variation

V_p : Set Threshold voltage
 A_p : Set Modulation Factor



Write-and-verify

~~D2D~~ variation



Related Work

Reliable Memristor-based Neuromorphic Design Using Variation- and Defect-Aware Training

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²Department of Electronic Design Automation, Technical University of Munich, Munich, Germany

*Corresponding Email: xzyin1@zju.edu.cn, czhuo@zju.edu.cn

First author (Year)	Non-idealities	Model-aware training	Post-fabrication training	Remapping	Hardware redundancy	Sensitivity analysis	Time to market
Gaol (2021) [8]	SAF, PV*	X	X	X	-	X	High
Jin (2020) [10]	SAF	-	X	X	-	X	High
Xu (2021) [19]	SAF, PV	X	X	X	-	X	High
Liu (2017) [13]	SAF	X	X	X	X	X	High
Joksas (2020) [11]	SAF, PV, IR-drop	-	-	-	X	-	Low
ReMeCo	SAF, PV, IR-drop	-	-	-	X	X	Low

Reliable Memristor-based Neuromorphic Design

Using Variational Methods

Di Gao¹, Grace Li

¹College of Informa

²Department of Elec

*

On Improving Fault Tolerance of Memristor Crossbar Based Neural Network Designs by Target Sparsifying

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Songwei Pei

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Yu Wang

North China Electric Power University

Baoding, P. R. China

wangyu@ncepu.edu.cn

First author (Year)	Non-idealities	Model-aware training	Post-fabrication training	Remapping	Hardware redundancy	Sensitivity analysis	Time to market
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Xu (2021) [19]	SAF, PV	X	X	X	-	X	High
Liu (2017) [13]	SAF	X	X	X	X	X	High
Joksas (2020) [11]	SAF, PV, IR-drop	-	-	-	X	-	Low
ReMeCo	SAF, PV, IR-drop	-	-	-	X	X	Low

Reliable Memristor-based Neuromorphic Design

Using Variability On Improving Fault Tolerance of Memristor

Reliability-Driven Neuromorphic Computing Systems Design

Qi Xu¹, Junpeng Wang¹, Hao Geng², Song Chen¹, Xiaoqing Wen³

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²Department of Computer Science and Engineering, The Chinese University of Hong Kong

³Department of Computer Science and Networks, Kyushu Institute of Technology

{xuqi@,wjp97@mail, songch@}ustc.edu.cn, hgeng@cse.cuhk.edu.hk, wen@cse.kyutech.ac.jp

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Xu (2021) [19]	SAF, PV	X	X	X	-	X	High
Liu (2017) [13]	SAF	X	X	X	X	X	High
Joksas (2020) [11]	SAF, PV, IR-drop	-	-	-	X	-	Low
ReMeCo	SAF, PV, IR-drop	-	-	-	X	X	Low

Rescuing Memristor-based Neuromorphic Design with High Defects

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[‡]School of Microelectronics, University of Science and Technology of China

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{xuqi@, wjp97@mail, songch@}ustc.edu.cn, hgeng@cse.cuhk.edu.hk, wen@cse.kyutech.ac.jp

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Liu (2017) [13]	SAF	X	X	X	X	X	High
Joksas (2020) [11]	SAF, PV, IR-drop	-	-	-	X	-	Low
ReMeCo	SAF, PV, IR-drop	-	-	-	X	X	Low

Reliable memristor-based in-memory neuromorphic computation with committee machines—a universal method to deal with non-idealities in memristor-based neural networks

D. Joksas¹✉, P. Freitas², Z. Chai², W. H. Ng¹, M. Buckwell¹, C. Li³, W. D. Zhang², Q. Xia³,
A. J. Kenyon¹ & A. Mehonic¹✉

First author (Year)	Non-idealities	Model-aware training	Post-fabrication training	Remapping	Hardware redundancy	Sensitivity analysis	Time to market
Gaol (2021) [8]	SAF, PV*	X	X	X	-	X	High
Jin (2020) [10]	SAF	-	X	X	-	X	High
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Liu (2017) [13]	SAF	X	X	X	X	X	High
Joksas (2020) [11]	SAF, PV, IR-drop	-	-	-	X	-	Low
ReMeCo	SAF, PV, IR-drop	-	-	-	X	X	Low



ReMeCo: a novel redundancy-based framework to improve the reliability of memristor-based ANN PEs by addressing the non-idealities

Contribution II

ReMeCo Flow



0. Sensitivity analysis



ReMeCo Flow



0. Sensitivity analysis

- Using the **back-propagation** ANN training algorithm
 - Feed forward path
 - Error calculation
 - Backward propagation of error to neurons

ReMeCo Flow



0. Sensitivity analysis

- Using the **back-propagation** ANN training algorithm
 - Feed forward path
 - Error calculation
 - Backward propagation of error

Calculate the average error contribution of individual neurons

$$Sens_{neuron} = AVR_{j=0}^N \left(\frac{\partial E}{\partial \omega_{i,j}} \right)$$

ReMeCo Flow



0. Sensitivity analysis

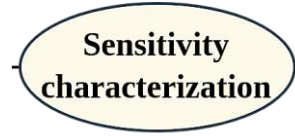
- Using the **back-propagation** ANN training algorithm
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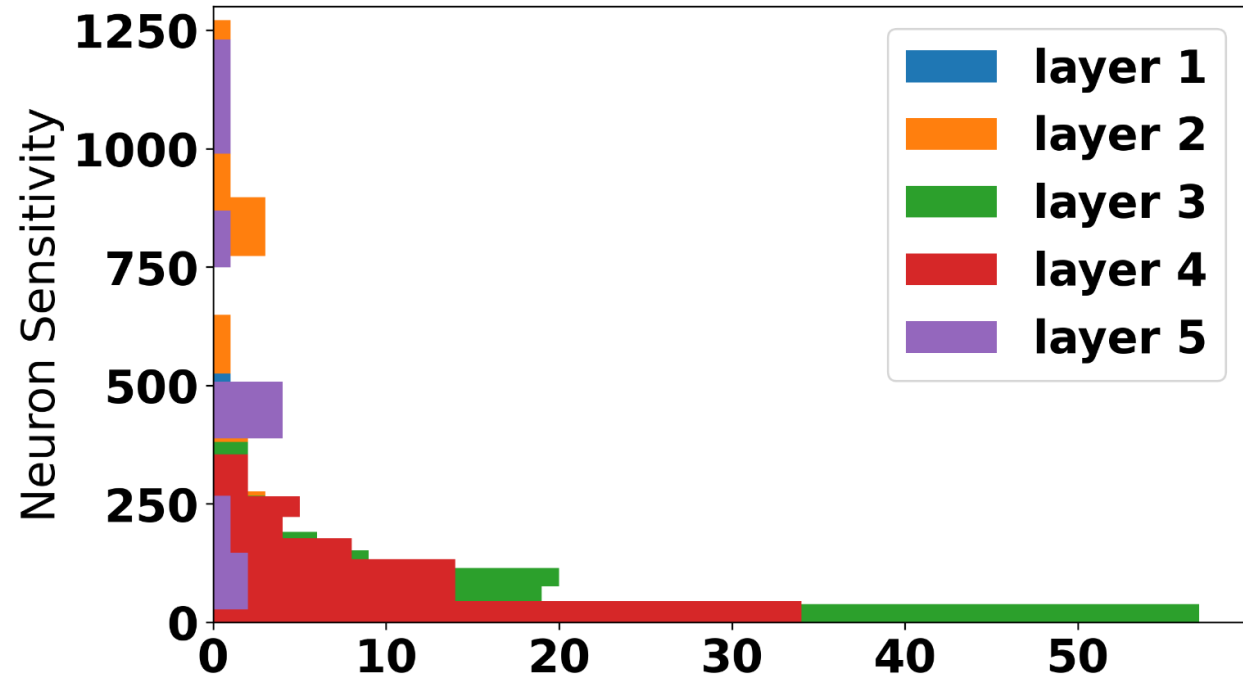
sensitivity of an ANN layer = average of the sensitivity of all its output neurons

ReMeCo Flow



0. Sensitivity analysis

- Absolute neuron sensitivity histogram for LeNet.



ReMeCo Flow

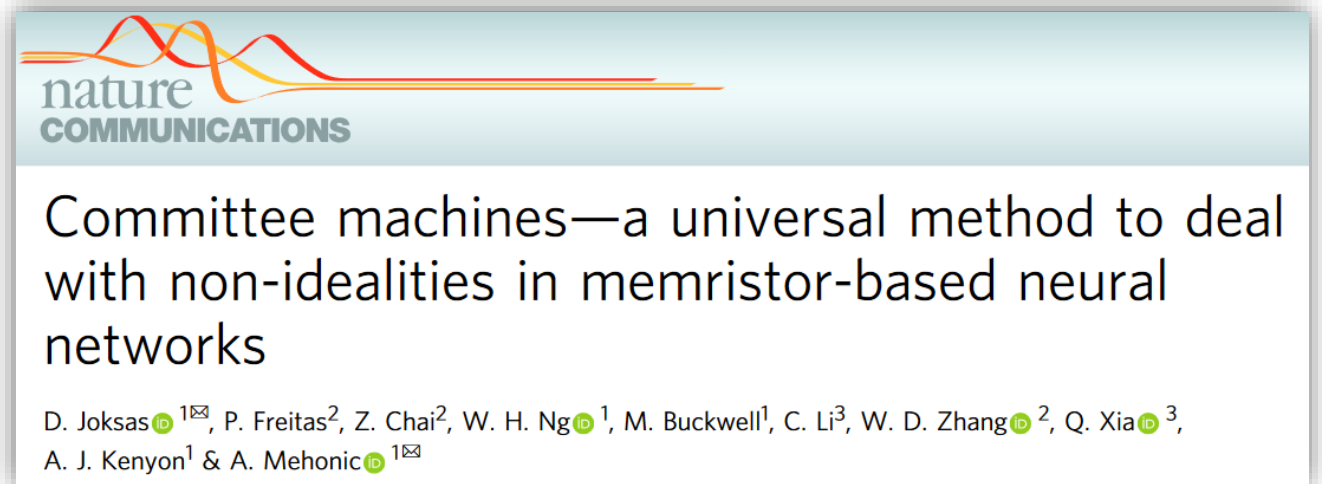
Committee Machine
(100% Redundancy)

Sensitivity
characterization

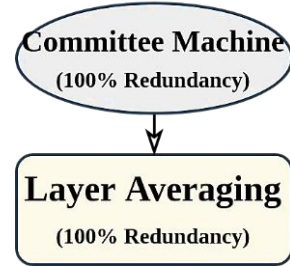
0. Sensitivity analysis

1. Start from the Committee Machine

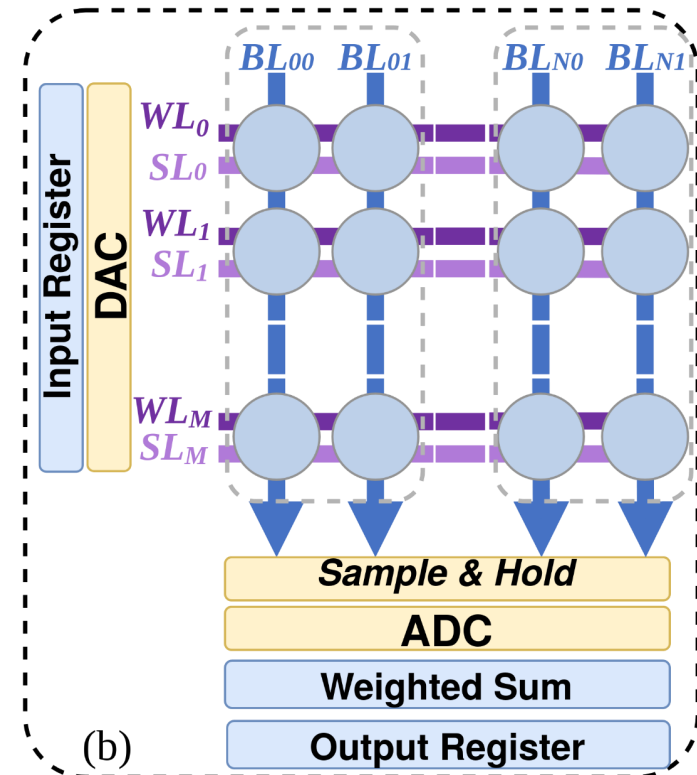
- Implements 1 ANN several times (2 times)
- Reports the average final output



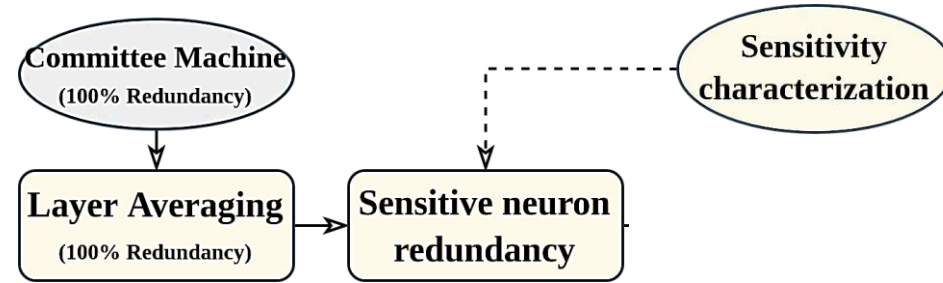
ReMeCo Flow



0. Sensitivity analysis
1. Start from the Committee Machine
2. Layer averaging



ReMeCo Flow

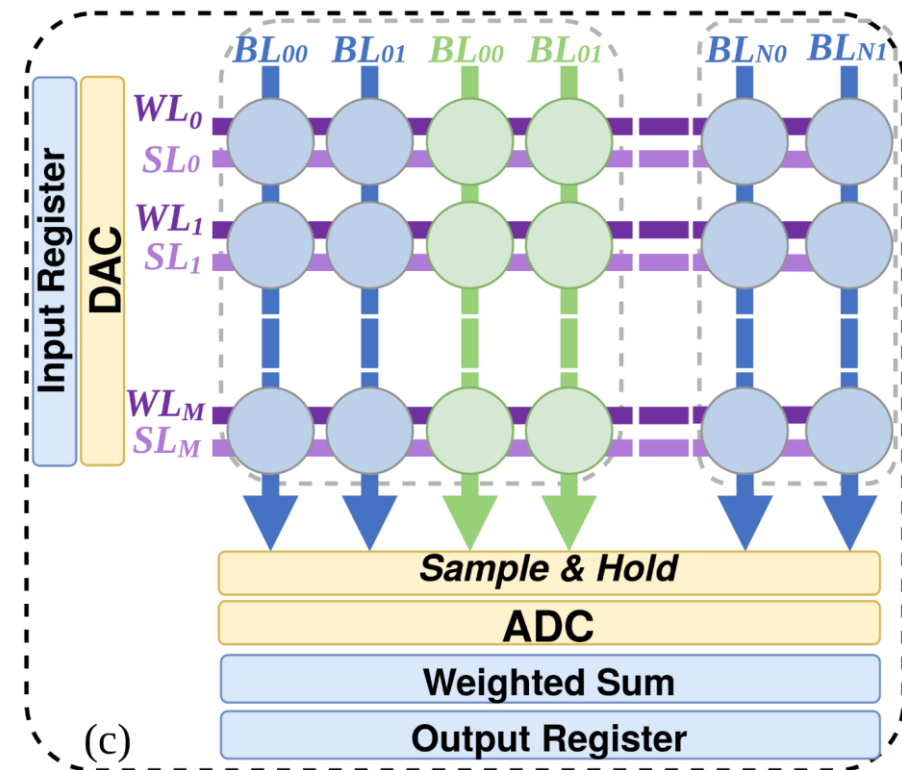


0. *Sensitivity analysis*

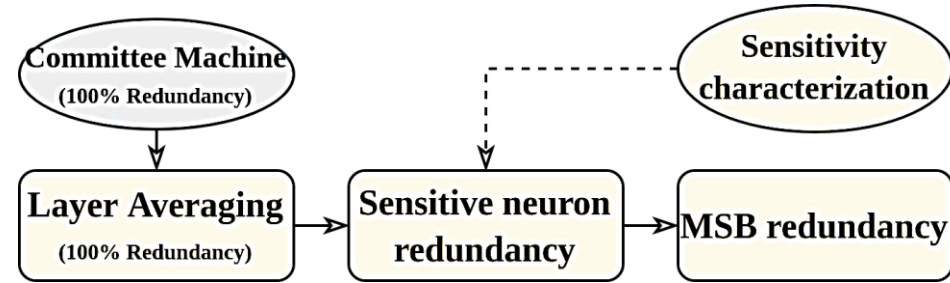
1. *Start from the Committee Machine*

2. *Layer averaging*

3. *Sensitive neuron redundancy*



ReMeCo Flow



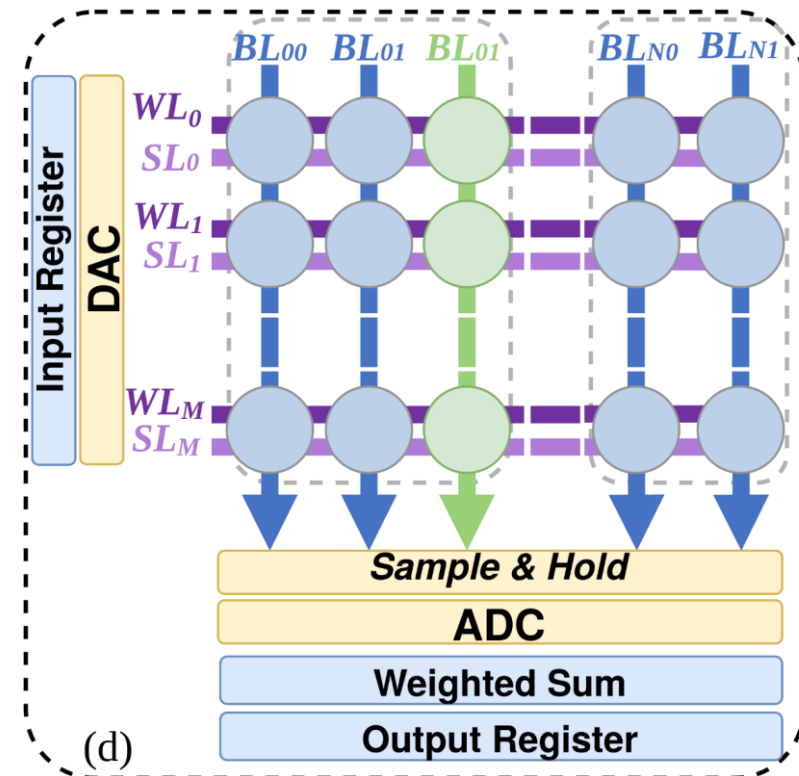
0. Sensitivity analysis

1. Start from the Committee Machine

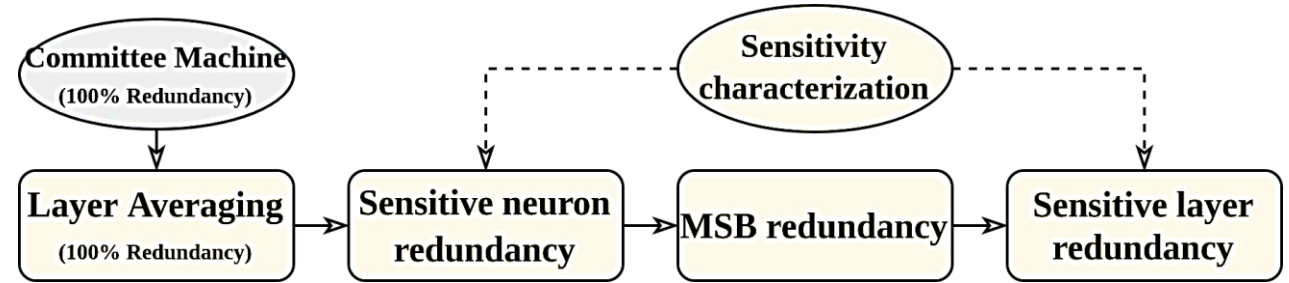
2. Layer averaging

3. Sensitive neuron redundancy

4. Most Significant Bit Redundancy



ReMeCo Flow



0. Sensitivity analysis

1. Start from the Committee Machine

2. Layer averaging

3. Sensitive neuron redundancy

4. Most Significant Bit Redundancy

5. Sensitive layer redundancy

Evaluations using LeNet and AlexNet (trained/tested with the MNIST and CIFAR-10 data-sets) show up to 98.5% accuracy recovery!

Contribution III



Benchmarks

- **LeNet** and **AlexNet** used for assessing ReMeCo
- Trained/tested with **MNIST** and **CIFAR-10** datasets
- **8-bit quantization**
- Achieved **software accuracy 98.8%** and **80.1%**

ANN	Data-set	Layers		Parameters	FLOPs
		Conv.	Dense		
LeNet	MNIST	2	3	866 K	28 M
AlexNet	CIFAR-10	5	3	62 M	1.5 B

Comparison

- We compare ReMeCo with Committee Machine (CM)
- Compare the ***recovered accuracy*** vs ***induced overhead***
- The lowest overhead for CM is considered (100% redundancy)

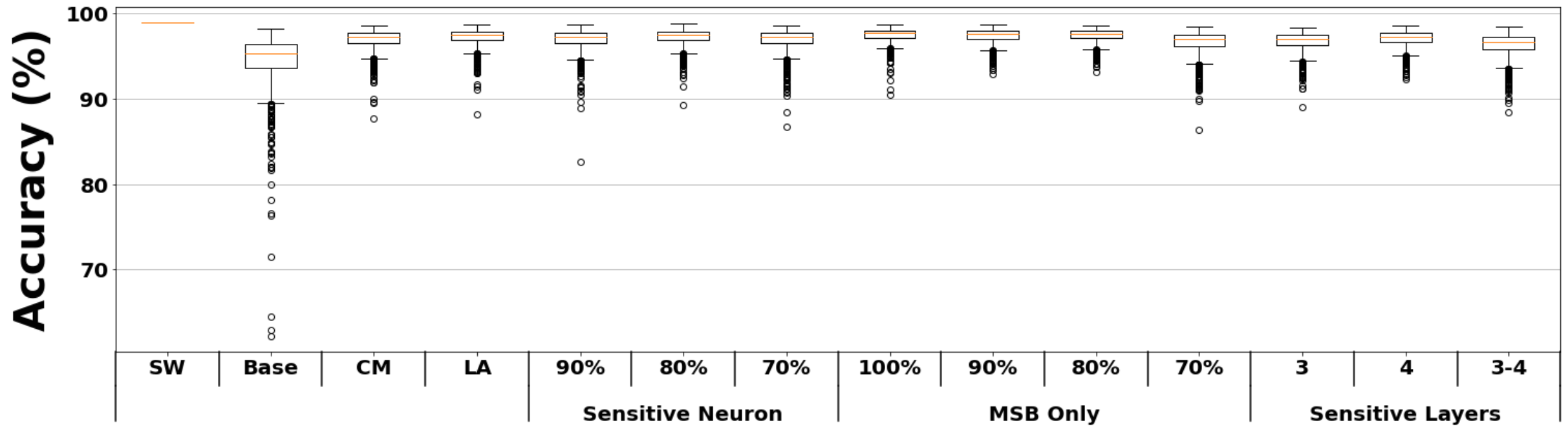


Implementation Notes

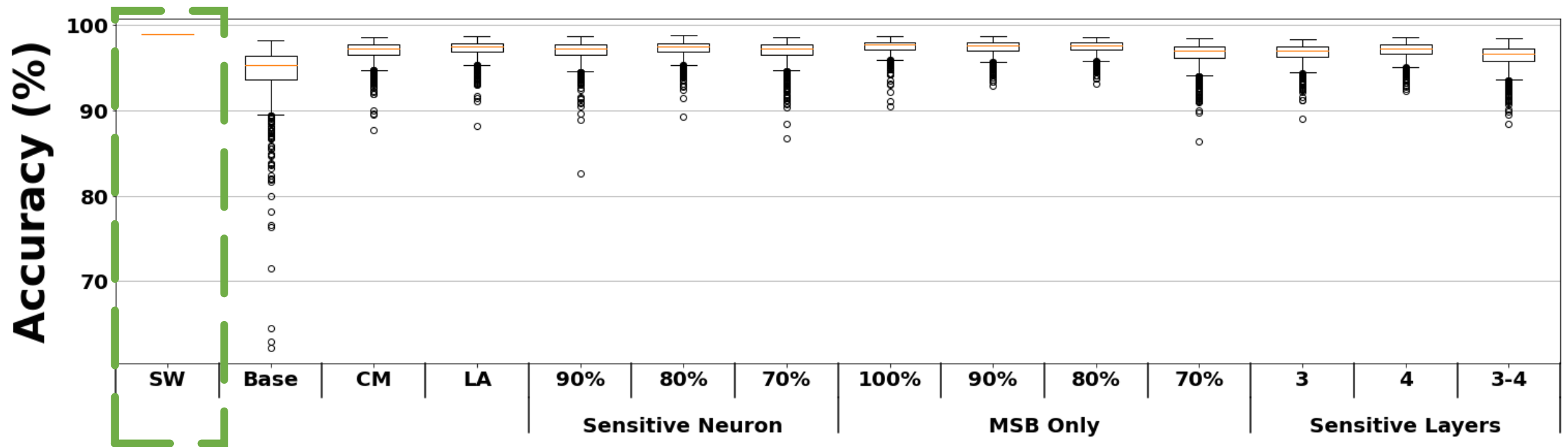
- 4-bit memristors are used (2 columns bit-slicing)
- Implement benchmarks on several **different crossbar models**
 - The source-line and bit-line resistance $\in N(\mu = 2, \sigma^2 = 0.5)$
 - In each circuit model, 1% of devices are randomly considered to be stuck
 - 16.2% of all stuck devices being stuck-at-off and 83.8% being stuck-at-on



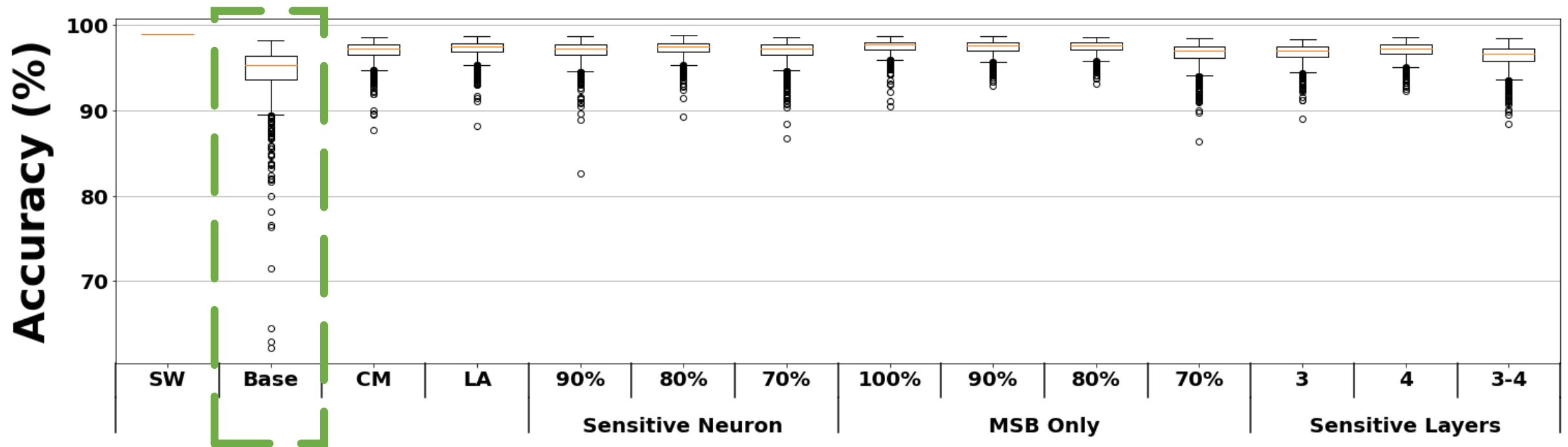
Results LeNet



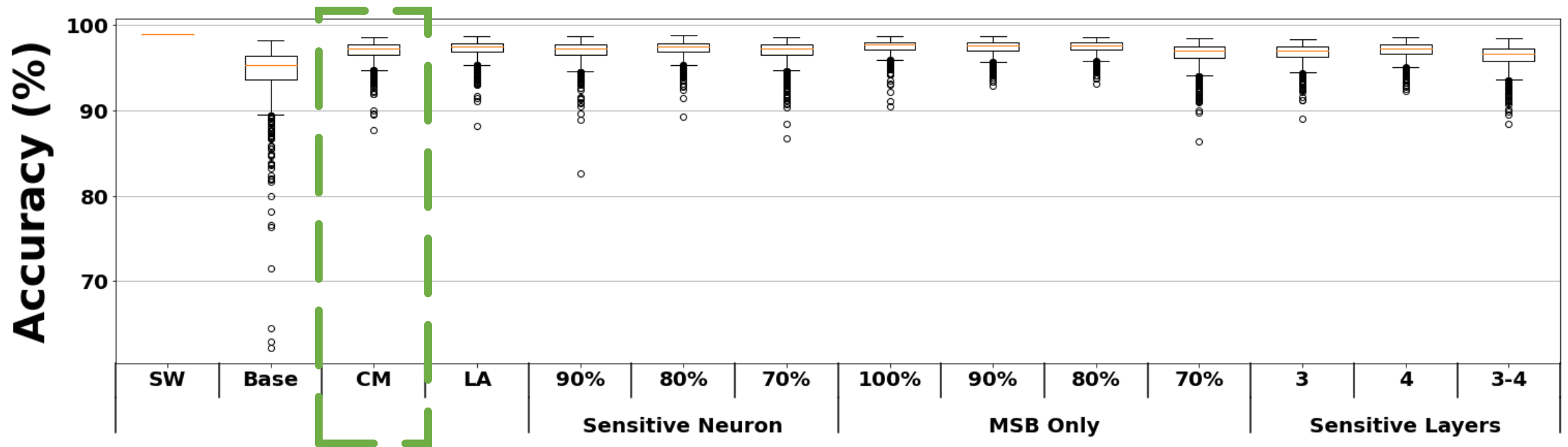
Results LeNet



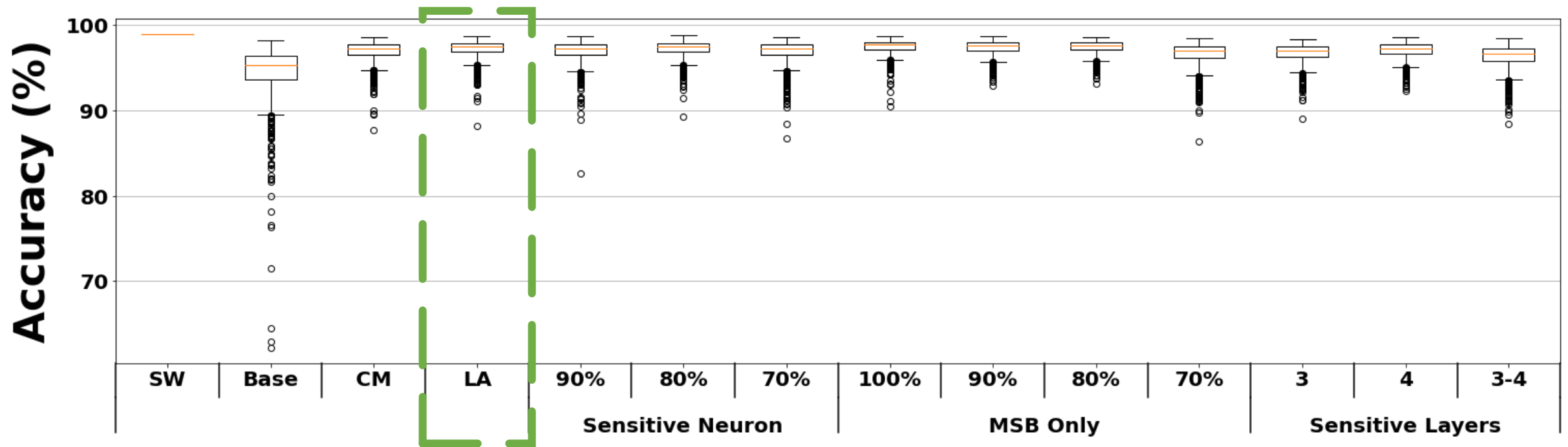
Results LeNet



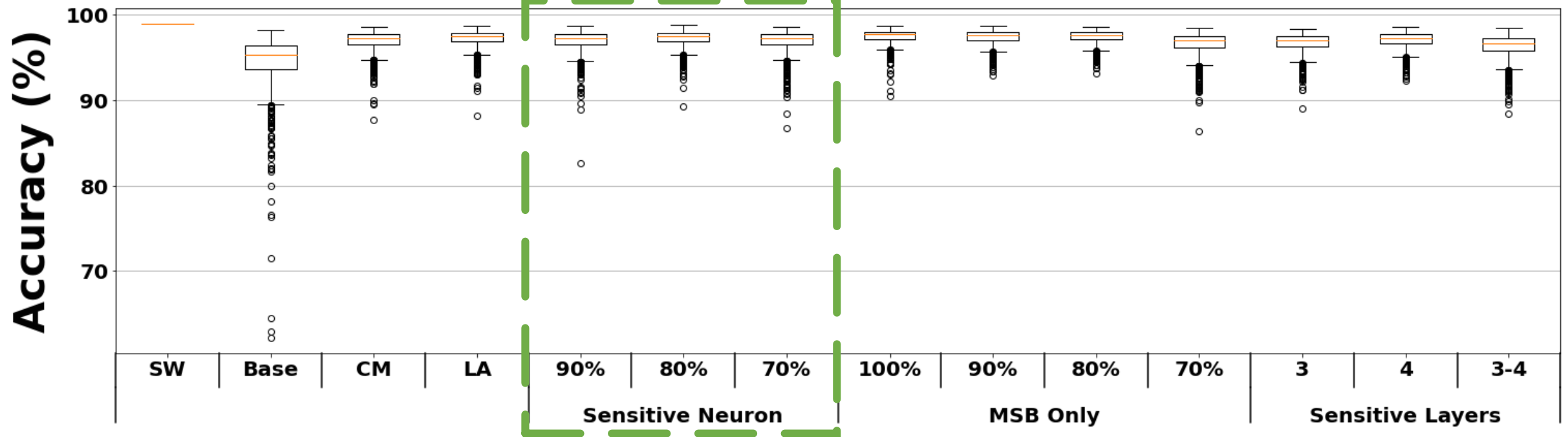
Results LeNet



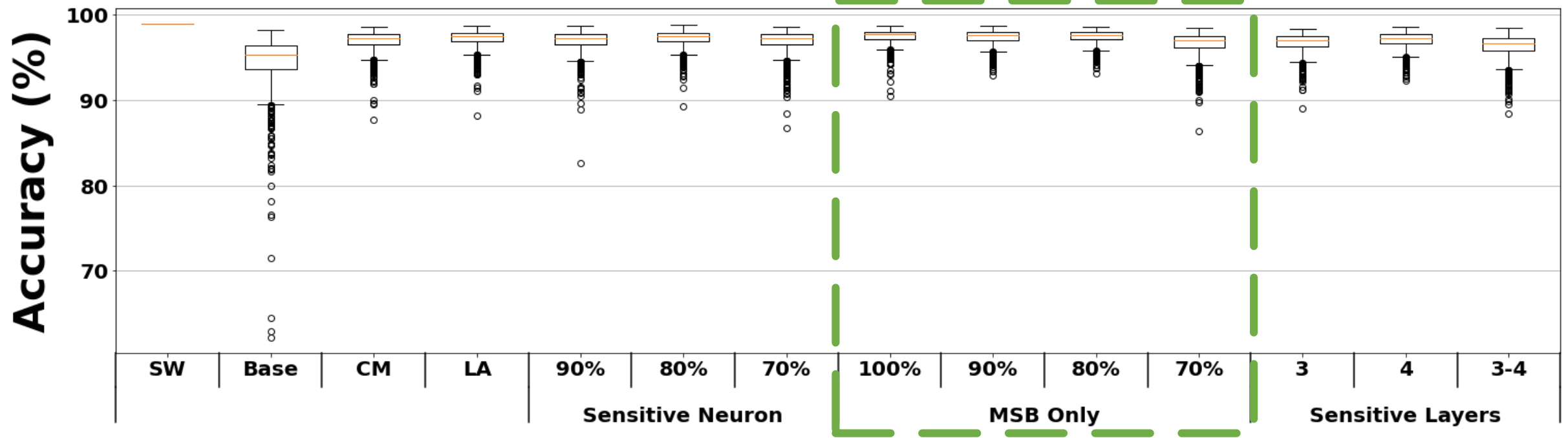
Results LeNet



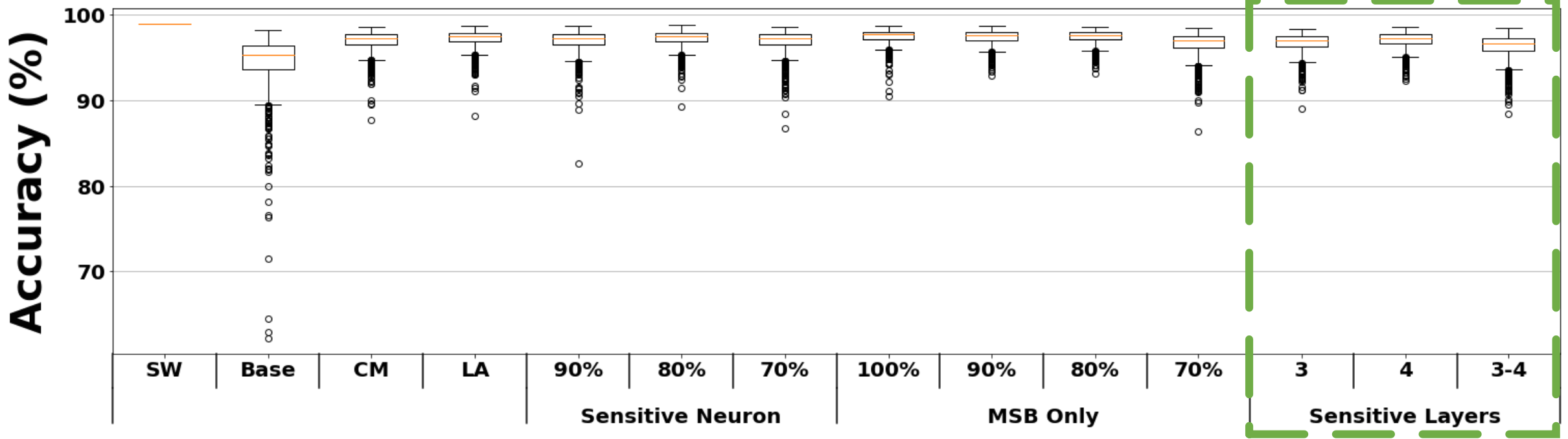
Results LeNet



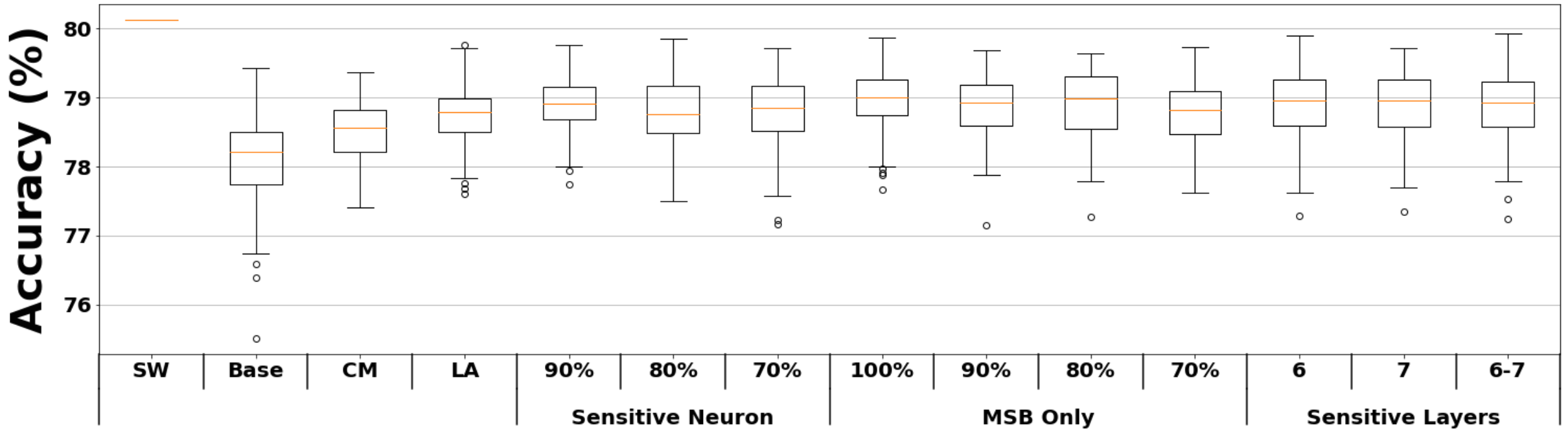
Results LeNet



Results LeNet



Results AlexNet



Results

ANN	Metric	Base (non-ideal)	Committee Machine	Layer Averaging	Sensitive neuron	MSB (80%)	Sensitive layer
LeNet	Accur.	94.4	96.9	97.2	97.2	97.4	96.4
	Area	7.23e-3	13.63e-3	13.64e-3	12.35e-3	9.79e-3	7.53e-3
	Energy	897.1	1791.2	1791.6	1612.7	1254.9	1211.1
AlexNet	Accur.	78.11	78.5	78.7	78.8	78.9	78.9
	Area	1.41	2.78	2.78	2.51	1.96	1.45
	Energy	1.84	3.68	3.68	3.31	2.58	2.54

Conclusion and Future Work

- We performed DSE to quantify the effects of different non-idealities
- We presented ReMeCo framework that addresses non-idealities.
- We achieved up to 98.5% accuracy recovery!
- We reduce HW overhead by +20x compared to CM!
- Future work, we perform tests on even deeper networks.